

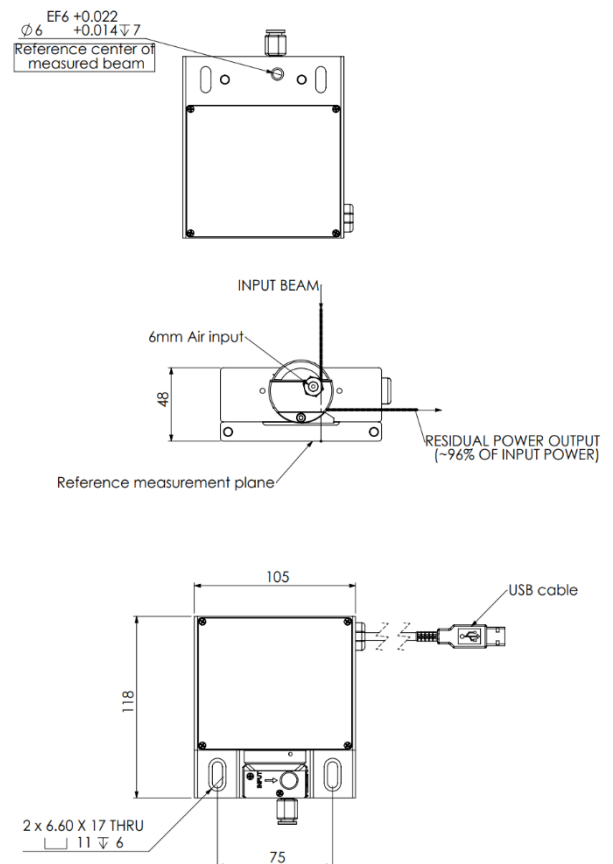
LAM Beam Analyzer



- High power beam measurements at the working tabletop.
- Built-in air-cooled sampler
- Industry's leading knife-edge system
- Unique tomographic image reconstruction
- Beam measurements down to 35 microns and up to 8 mm
- Accurately measures profile, position and power

Specifications

Sensor Type	Silicone (Si) - Knife-edge technology
Spectral Range	Si: 350 - 1100 nm. Contact factory for other wavelengths
Number of Blades	7 blades with image tomographic reconstruction
Beam Size Range	35 microns up to 8 mm
Beam-width resolution	For beams > 100 μm in size: 1 μm . For beams <100 μm in size: 0.1 μm
Beam-width accuracy	$\pm 2\%$
Power Range	Up to 4 kW (with filters & pressurized air-cooling, some restrictions may apply)
Power Accuracy	$\pm 5\%$
Position Accuracy	$\pm 15 \mu\text{m}$
Position Resolution	1 μm
Measurement Rate	5 Hz
Weight	Sensor head with cable ~ 1500 gr.
PC Interface	USB 2.0 (PCI optional)
Optional Accessories:	ND Optical Filters



Ordering Information

LAM-BA: 7-blades, Si detector with high power attenuator and mounting adapter.

DUMA OPTRONICS LTD.